**Product data sheet** 

# 1. General description

Planar passivated high commutation three quadrant triac in a SOT223 surface mountable plastic package. This triac is intended for use in motor control circuits where very high blocking voltage can occur. It is used in applications where "high junction operating temperature capability ( $T_{j(max)} = 150 \, ^{\circ}$ C)" is required.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- High junction operating temperature capability (T<sub>j(max)</sub> = 150 °C)
- Over-voltage withstand capability to IEC 61000-4-5
- · Planar passivated for voltage ruggedness and reliability
- High voltage capability
- · High immunity to false tun on by dV/dt
- · Triggering in three quadrants only
- Surface mountable package

## 3. Applications

- AC fan, pump and compressor controls
- · Highly inductive, resistive and safety loads
- Large and small appliances (White Goods)
- · Reversing induction motor controls e.g. vertical axis washing machines

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	-	1000	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>sp</sub> ≤ 117 °C; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>	-	-	2	A
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms; Fig. 4; Fig. 5	-	-	25	А
		full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ ms}$	-	-	27.5	Α
T <sub>j</sub>	junction temperature		-	-	150	°C
Static ch	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	10	mA

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>		-	-	25	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 3 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>		-	-	1.5	V
Dynamic	Dynamic characteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 670 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit		600	-	-	V/µs

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		2
2	T2	main terminal 2		T2 T1
3	G	gate		sym051
4	mb	mounting base; connected to main terminal 2	□1 □2 □3	

# 6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA202W-1000ET	SOT223	BTA202W-1000ETF	Reel	4000	SOT223	16-Mar-2006

## 7. Marking

### **Table 4. Marking codes**

Type number	Marking codes
BTA202W-1000ET	2W
	1000ET

# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	1000	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{sp} \le 117 ^{\circ}\text{C}$ ; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>	-	2	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms; Fig. 4; Fig. 5	-	25	А
		full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 16.7 ms	-	27.5	Α
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; sine wave pulse	-	3.125	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 20 mA	-	100	A/µs
I <sub>GM</sub>	peak gate current		-	2	А
$P_{GM}$	peak gate power		-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C

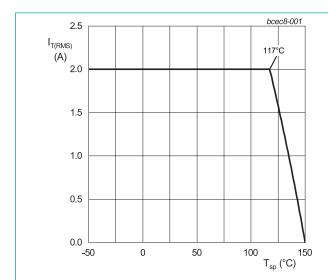
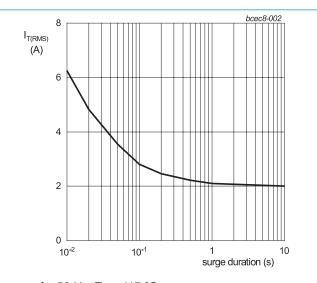
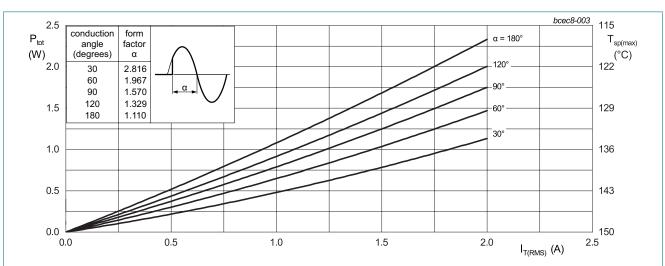


Fig. 1. RMS on-state current as a function of solder point temperature; maximum values



 $f = 50 \text{ Hz}; T_{sp} = 117 \text{ }^{\circ}\text{C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values



a = form factor =  $I_{T(RMS)} / I_{T(AV)}$ 

 $\alpha$  = conduction angle

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

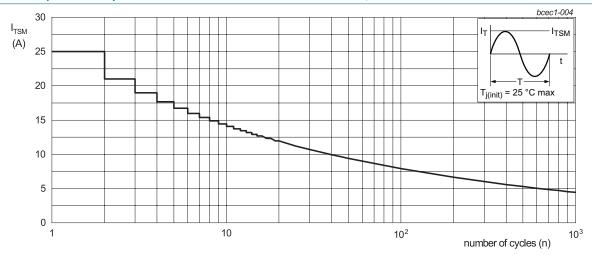
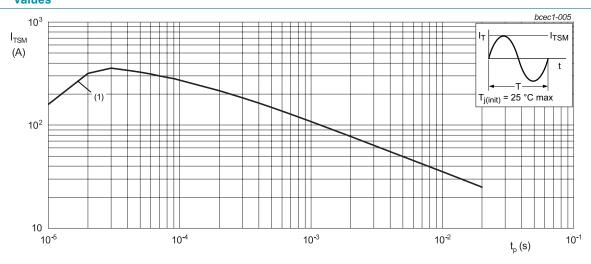


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_p \le 20 \text{ ms}$ (1)  $dI_T/dt \text{ limit}$ 

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

## 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point	<u>Fig. 6</u>	-	-	14	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to	in free air; printed circuit board mounted; minimum pad area; <u>Fig. 7</u>	-	70	-	K/W
	ambient	in free air; printed circuit board mounted; minimum footprint; <u>Fig. 8</u>	-	156	-	K/W

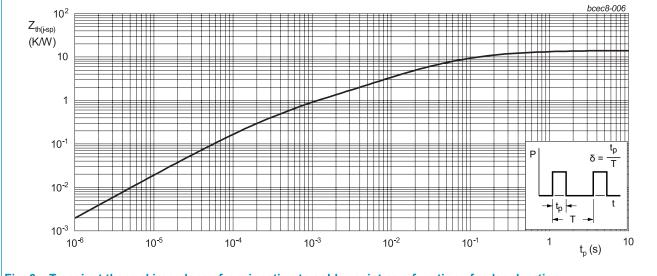
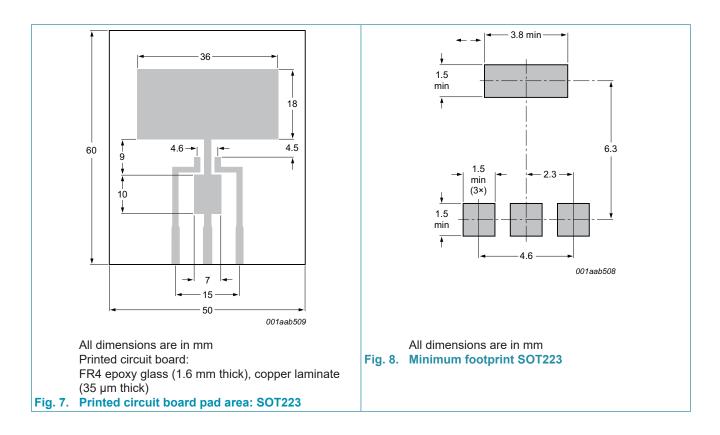


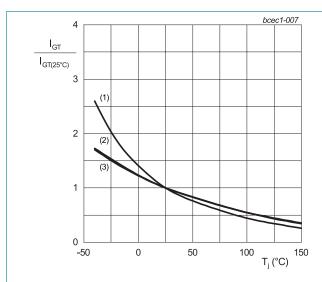
Fig. 6. Transient thermal impedance from junction to solder point as a function of pulse duration



## 10. Characteristics

**Table 7. Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I <sub>GT</sub> gate trigger current		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 9$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G -; $ $T_j = 25 \text{ °C; } Fig. 9$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; Fig. 9}$	-	-	10	mA
I <sub>L</sub>	latching current	V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G+; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	40	mA
		V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2+ G-; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	50	mA
		V <sub>D</sub> = 12 V; I <sub>G</sub> = 0.1 A; T2- G-; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	40	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	-	25	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 3 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>	-	-	1.5	V
V <sub>GT</sub> gat	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C}$ Fig. 13	-	8.0	1	V
		$V_D = 400 \text{ V; } I_T = 0.1 \text{ A; } T_j = 150 ^{\circ}\text{C}$	0.2	0.45	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 1000 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>D</sub> = 1000 V; T <sub>j</sub> = 150 °C	-	-	1	mA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 1000 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>R</sub> = 1000 V; T <sub>j</sub> = 150 °C	-	-	1	mA
Dynamic	characteristics		'			
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 670 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	600	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 2 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	2	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 2 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; gate open circuit}$	3	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 2 \text{ A;}$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s; gate open circuit}$	4	-	-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 9. Normalized gate trigger current as a function of junction temperature

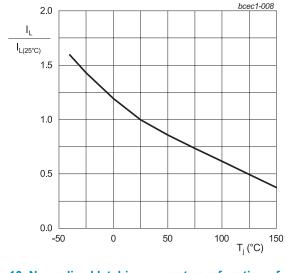


Fig. 10. Normalized latching current as a function of junction temperature

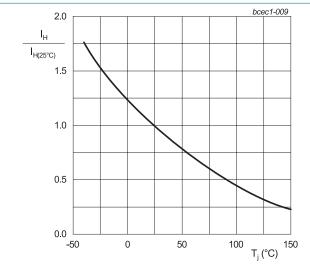
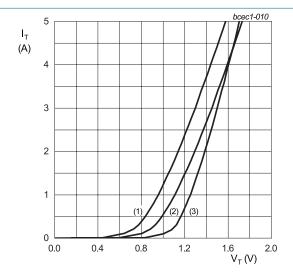


Fig. 11. Normalized holding current as a function of junction temperature



 $V_o = 1.101 \text{ V}; R_s = 0.0875 \Omega$ 

(1) T<sub>i</sub> = 150 °C; typical values

(2) T<sub>i</sub> = 150 °C; maximum values

(3)  $T_i = 25$  °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

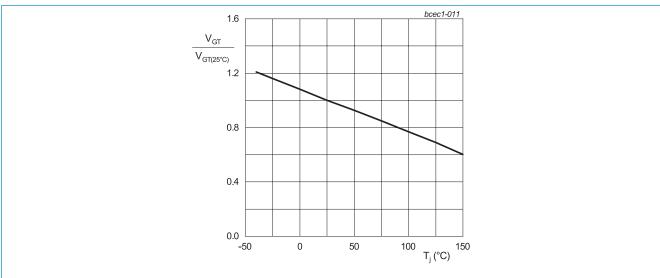
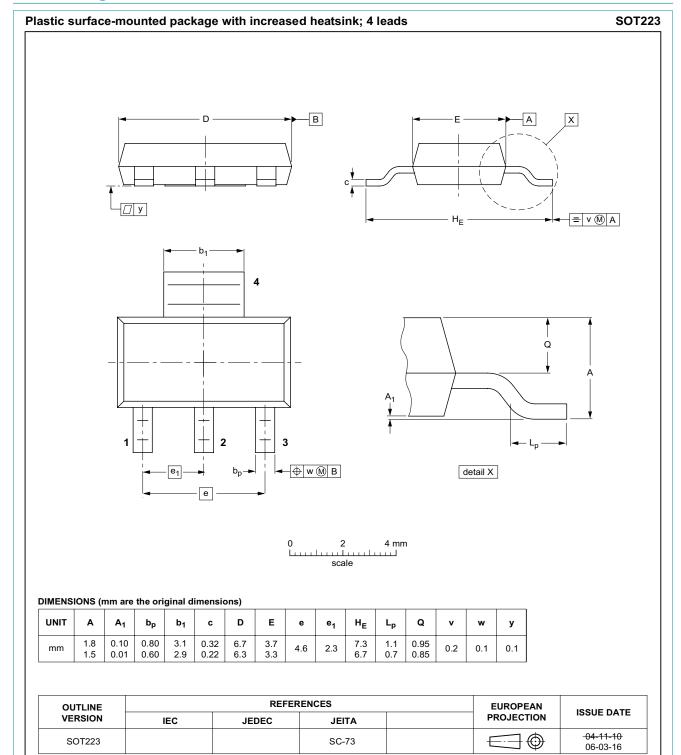


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

# 11. Package outline



### 12. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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